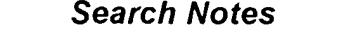


<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>
	10/709,179	CHANG ET AL.
	<b>Examiner</b>	Art Unit
	Nathan W. Ha	2814

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner